2SC3824, 2SC3824A

Silicon NPN triple diffusion planar type

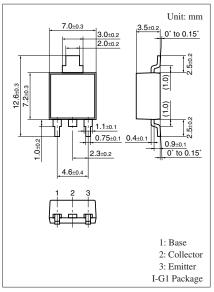
For high breakdown voltage high-speed switching

■ Features

- High-speed switching
- \bullet High collector-base voltage (Emitter open) V_{CBO}
- I type package enabling direct soldering of the radiating fin to the printed circuit board, etc. of small electronic equipment

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (En	V _{CBO}	900	V	
Collector-emitter voltage	V _{CES}	900	V	
Collector-emitter voltage	2SC3824	V _{CEO}	800	V
(Base open)	2SC3824A		900	
Emitter-base voltage (Col	V_{EBO}	7	V	
Collector current	I_C	1	A	
Peak collector current	I_{CP}	2	A	
Collector power	P _C	15	W	
dissipation	$T_a = 25^{\circ}C$		1.3	
Junction temperature	T_j	150	°C	
Storage temperature	T_{stg}	-55 to +150	°C	

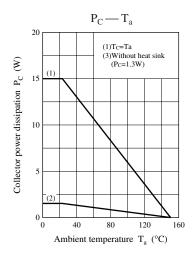


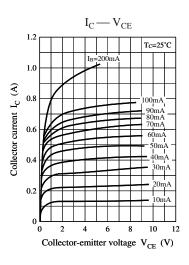
Note) Self-supported type package is also prepared.

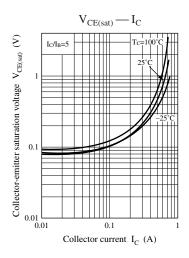
■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

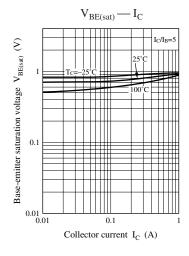
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SC3824	V _{CEO}	$I_C = 1 \text{ mA}, I_B = 0$	800			V
(Base open)	2SC3824A			900			
Collector-base cutoff current (E	mitter open)	I_{CBO}	$V_{CB} = 900 \text{ V}, I_{E} = 0$			50	μΑ
Emitter-base cutoff current (Collector open)		I_{EBO}	$V_{EB} = 7 \text{ V}, I_{C} = 0$			50	μΑ
Forward current transfer ratio		h _{FE1}	$V_{CE} = 5 \text{ V}, I_{C} = 0.05 \text{ A}$	6			_
		h _{FE2}	$V_{CE} = 5 \text{ V}, I_{C} = 0.5 \text{ A}$	3			
Collector-emitter saturation voltage		V _{CE(sat)}	$I_C = 0.2 \text{ A}, I_B = 0.04 \text{ A}$			1.5	V
Base-emitter saturation volt	age	V _{BE(sat)}	$I_C = 0.2 \text{ A}, I_B = 0.04 \text{ A}$			1.0	V
Transition frequency		f_T	$V_{CE} = 10 \text{ V}, I_{C} = 0.05 \text{ A}, f = 1 \text{ MHz}$		4		MHz
Turn-on time		t _{on}	$I_C = 0.2 \text{ A}$			1.0	μs
Storage time		t _{stg}	$I_{B1} = 0.04 \text{ A}, I_{B2} = -0.08 \text{ A}$			3.0	μs
Fall time		t _f	$V_{CC} = 250 \text{ V}$			1.0	μs

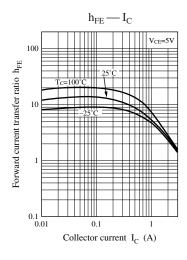
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

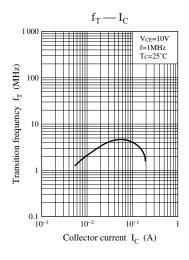


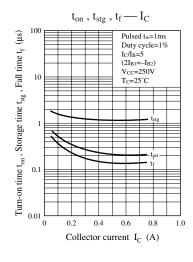


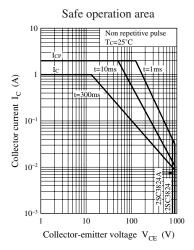






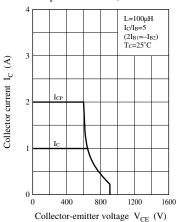




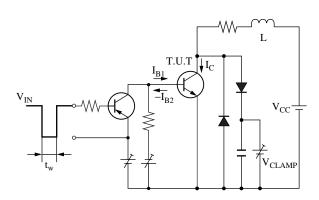


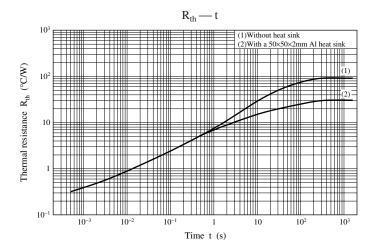
2 SJD00113AED

Safe operation area (Reverse bias)



Safe operation area (Reverse bias) measurement circuit





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